

**High Resolution High Resonance frequency Semicontact / Noncontact AFM Cantilevers HA HR series with W2C+ tip conductive coating for long time work in electrical AFM modes, each chip has 2 cantilevers, resonant frequency 380 kHz / 230 kHz, force constant 34 N/m / 17 N/m**

Art. ID	TIPS-HA_HR/W2C+/300
Unit	300 separated chips
Deliverydetails	No Dangerous Good /not restricted

Description

High Resolution High Resonant Frequency AFM Cantilevers HA\_HR/W2C+ series are designed for Semicontact ( Intermittent ), Noncontact and electrical applications (SKM, SCM, SRIM, EFM, LAO Lithography) / Hard and stable coating provides long time performance in all electrical modes. Specially doped W2C+ coating allows to avoid probes from oxidation, extends probe lifetime and makes it possible to operate at high-humidity conditions / Each probe has 2 rectangular cantilevers. Typical Resonant Frequency 380kHz / 230kHz (dispersion  $\pm 10\%$ ), Typical Force Constant 34N/m / 17N/m (dispersion  $\pm 20\%$ ). Cantilever has Au reflective and W2C tip side coatings. Probes are also available without tip coating / Probes are packed in boxes with 15 and 50 pieces. Amount discount is included in the package price / High Accuracy composite ETALON probes combine the main features allowing to obtain high quality AFM images: Sharp tip - curvature radius < 10 nm. /// Resonance frequency, specified with high accuracy -  $\pm 10\%$  within a wafer. /// Special chip geometry with vertical sidewalls for convenient operating. /// High aspect ratio tip. /// Enhanced back-side reflection of the cantilever. /// Cost effective price.